Charles A Clifford

List of Publications by Year
in descending order

35	1,307	516215 16	433756 31
papers	citations	h-index	g-index

36	36	36	1777
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Composition, thickness, and homogeneity of the coating of coreâ€“shell nanoparticlesâ€”possibilities, limits, and challenges of X-ray photoelectron spectroscopy. Analytical and Bioanalytical Chemistry, 2022, , 1.	1.9	3
2	Particle size distributions for cellulose nanocrystals measured by atomic force microscopy: an interlaboratory comparison. Cellulose, 2021, 28, 1387-1403.	2.4	27
3	The importance of international standards for the graphene community. Nature Reviews Physics, 2021, 3, 233-235.	11.9	19
4	Summary of ISO/TC 201 Technical Report 23173â€”Surface chemical analysisâ€”Electron spectroscopiesâ€”Measurement of the thickness and composition of nanoparticle coatings. Surface and Interface Analysis, 2021, 53, 893-898.	0.8	3
5	Characterizing the nanomechanical properties of microcomedones after treatment with sodium salicylate ex vivo using atomic force microscopy. International Journal of Cosmetic Science, 2021, 43, 610-618.	1.2	4
6	Nanomechanical properties of potato flakes using atomic force microscopy. Journal of Food Engineering, 2021, 307, 110646.	2.7	3
7	International standards in nanotechnologies. , 2020, , 511-525.		7
8	Response to ACS Nano Editorial â€œStandardizing Nanomaterialsâ€. ACS Nano, 2020, 14, 14255-14257.	7.3	4
9	Calibrated Kelvin-probe force microscopy of 2D materials using Pt-coated probes. Journal of Physics Communications, 2020, 4, 095025.	0.5	10
10	Summary of ISO/TC 201 Standard: ISO 22415â€”Surface chemical analysisâ€”Secondary ion mass spectrometryâ€”Method for determining yield volume in argon cluster sputter depth profiling of organic materials. Surface and Interface Analysis, 2019, 51, 1018-1020.	0.8	2
11	Towards standardising electron spectroscopy measurement of nanoparticle coatings. Journal of Surface Analysis (Online), 2019, 26, 164-165.	0.1	1
12	Summary of ISO/TC 201 standard: ISO 19668â€”Surface chemical analysisâ€”Xâ€ray photoelectron spectroscopyâ€”Estimating and reporting detection limits for elements in homogeneous materials. Surface and Interface Analysis, 2018, 50, 87-89.	0.8	4
13	Importance of sample preparation on reliable surface characterisation of nanoâ€objects: ISO standard 20579â€4. Surface and Interface Analysis, 2018, 50, 902-906.	0.8	14
14	Terminology: the first step towards international standardisation of graphene and related 2D materials. Journal of Materials Science, 2017, 52, 13685-13688.	1.7	14
15	Summary of ISO/TC 201 standard: ISO 11775:2015 â€“ Surface chemical analysis â€“ Scanning probe microscopy â€“ Determination of cantilever normal spring constants. Surface and Interface Analysis, 2017, 49, 171-172.	0.8	0
16	Challenges in the size analysis of a silica nanoparticle mixture as candidate certified reference material. Journal of Nanoparticle Research, 2016, 18, 171.	0.8	68
17	Towards easy and reliable AFM tip shape determination using blind tip reconstruction. Ultramicroscopy, 2014, 146, 130-143.	0.8	58
18	Development of a Novel Combined Scanning Electrochemical Microscope (SECM) and Scanning Ion-Conductance Microscope (SICM) Probe for Soft Sample Imaging. Materials Research Society Symposia Proceedings, 2012, 1422, 13.	0.1	2

#	Article	IF	Citations
19	Modelling of surface nanoparticle inclusions for nanomechanical measurements by an AFM or nanoindenter: spatial issues. Nanotechnology, 2012, 23, 165704.	1.3	14
20	Nanomechanical measurements of hair as an example of micro-fibre analysis using atomic force microscopy nanoindentation. Ultramicroscopy, 2012, 114, 38-45.	0.8	17
21	Multifunctional Nanoprobes for Nanoscale Chemical Imaging and Localized Chemical Delivery at Surfaces and Interfaces. Angewandte Chemie - International Edition, 2011, 50, 9638-9642.	7.2	256
22	Sample preparation protocols for realization of reproducible characterization of single-wall carbon nanotubes. Metrologia, 2009, 46, 682-692.	0.6	36
23	Nanoindentation measurement of Youngâ€™s modulus for compliant layers on stiffer substrates including the effect of Poissonâ€™s ratios. Nanotechnology, 2009, 20, 145708.	1.3	34
24	Simplified drift characterization in scanning probe microscopes using a simple two-point method. Measurement Science and Technology, 2009, 20, 095103.	1.4	23
25	Improved methods and uncertainty analysis in the calibration of the spring constant of an atomic force microscope cantilever using static experimental methods. Measurement Science and Technology, 2009, 20, 125501.	1.4	31
26	Cantilever Spring-Constant Calibration in Atomic Force Microscopy. , 2008, , 289-314.		9
27	Modelling of Nanoindentation of Compliant Layers on Stiffer Substrates using Finite Element Analysis. Materials Research Society Symposia Proceedings, 2007, 1025, 1.	0.1	0
28	Modelling of nanomechanical nanoindentation measurements using an AFM or nanoindenter for compliant layers on stiffer substrates. Nanotechnology, 2006, 17, 5283-5292.	1.3	76
29	Quantification issues in the identification of nanoscale regions of homopolymers using modulus measurement via AFM nanoindentation. Applied Surface Science, 2005, 252, 1915-1933.	3.1	147
30	An accurate semi-empirical equation for sputtering yields I: for argon ions. Surface and Interface Analysis, 2005, 37, 444-458.	0.8	112
31	Microelectromechanical device for lateral force calibration in the atomic force microscope: Lateral electrical nanobalance. Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena, 2005, 23, 1992.	1.6	36
32	The determination of atomic force microscope cantilever spring constants via dimensional methods for nanomechanical analysis. Nanotechnology, 2005, 16, 1666-1680.	1.3	166
33	Microelectromechanical system device for calibration of atomic force microscope cantilever spring constants between 0.01 and 4 N/m. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2004, 22, 1444-1449.	0.9	12
34	Quantitative analytical atomic force microscopy: a cantilever reference device for easy and accurate AFM spring-constant calibration. Measurement Science and Technology, 2004, 15, 1337-1346.	1.4	74
35	Surface kinetics using line of sight techniques: the reaction of chloroform with Cu(111). Physical Chemistry Chemical Physics, 1999, 1, 5223-5228.	1.3	21